

Fabrication of Si, Si3N4 & InGaAsP Optical Metasurfaces with Dry Etching Lidan Zhang

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- Background
- Optical Metasurfaces based on Dry etching
 - aSi wafer scale metalens fabricated by dry etch
 - Si3N4 double-layer achromatic metalens fabricated by dry etch
 - III-V OAM and BIC lasers fabricated by dry etch
- Summary

Metasurface – Tailoring light properties in the nanoscale





Low loss, small footprint, easy fabrication and integration, low cost, etc.

Plasmonic resonance



S. Sun, et. al. Nano Lett., (2012)

Mie resonance



M. Decker, et al. Adv. Opt. Mat., (2015)

Pancharatnam–Berry phase



G. Zheng, et al. Nat. Nanotech., (2015)

Applications of metasurfaces





H. Liu, et al. Nat. Phys., (2018)

M. A. Gorlach. et al. Nat. Commun., (2018)





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Seeing colorful world with Lenses





Cellphone



Digital Camera Conventional lenses: Bulky, Heavy Expensive, Hard to fabricate Metalens: lightweight, ultrathin





Dielectric metalenses: Low loss, strong light confinement

Design and fabrication of wafer-scale metalens





Required phase profile:

$$\varphi(r) = -\frac{2\pi}{\lambda} \left[\sqrt{(r^2 + f^2)} - f \right]$$

aSi Metalens with different mask and etching recipe



Alcatel Speeder 100 SiO₂









aSi Metalens with different etching gas





Wafer-scale Metalens



Alcatel Speeder 100 SiO₂



Oxford Cobra







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Metalens – lightweight, manipulate aberration





metalens: metaphotonic device which can function like normal lens



Nano Lett.17.3 (2017)

Nat. Nanotechnol. 13.3 (2018)

Nano Lett. 18.12 (2018)

Design Principle





Different SiNx etching with different etching recipe



Low dispersive SiNx



high dispersive SiNx





SiNx metasurfaces with different etching recipe









Plasma-Therm Versalock

By courtesy of Yao Duan and Shengyuan Chang 15



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Light with **orbital angular momentum (OAM)** has an **azimuthal** phase term $e^{il\varphi}$, travelling with a twisted helical wavefront.



https://en.wikipedia.org/wiki/Orbital_angular_momentum_of_light

By courtesy of Xuexue Guo

Integrated OAM microring lasers





$$l_{OAM}\varphi = \phi_{OAM} = \phi_{CCW} + \phi_{ms} = \beta_{CCW}R\varphi - \frac{2\pi}{\Lambda}R\varphi.$$

 $l_{OAM} = M - N$ M - WGM orderN - number of supercells

- Breaking CW and CCW mode degeneracy with asymmetric phase gradient
- OAM order can be tuned

Science advances 6.29 (2020): eabb4142.

By courtesy of Xuexue Guo



Convention method: CH4/H2/Ar ---- slow etch rate and chamber contamination

BCl₃ 30 sccm, 2 mT, chuck power: 200W, chuck temperature: 80 °C, no helium cooling



Scale bar: 1 µm.

ULVAC NE-550 Etching System

Characterization of OAM microring laser





The microring consists of a 500-nm InGaAsP multi-quantum-well layer, a 1- μ m InP layer and an array of metasurfaces with N = 58 supercells.

Science advances 6.29 (2020): eabb4142.

Suspended MQW Structures

- Objective:
 - Suspended InGaAsP structures for laser purpose
 - elliptical holes with axis diameter varying from 200 nm to 600 nm



InGaAsP (505 nm) InP (1000 nm) InGaAs (100 nm) InP substrate

- Bulk blue region must penetrate InGaAs layer (> 1605 nm)
- holes region must be moderate deep for promoting wet etch (>1000 nm)



Dry Etch in CI-Based Chemistry



Proper window: 190 ~ 250 °C



Hole diameter (nm)

FIG. 2. Arrhenius plots of the etch rate for process 1 (250 W/-640 V) and process 2 (1000 W/-230 V). The temperatures used are the real estimated temperatures of the sample. Insert SEM micrographs show surfaces etched with process 2.

Carlström C F, et al. Journal of Vacuum Science & Technology B: Microelectronics and Nanometer Structures Processing, Measurement, and Phenomena, 2008, 26(5): 1675-1683.

Etch rate is very slow $< 190 \,^{\circ}C$

Etch lag is large > 280 °C (on Si carrier wafer)

Control RIE lag

Suspended InGaAsP photonic crystal





ULVAC NE-550 Etching System

Summary



aSi wafer-scale metalens



InGaAsP OAM laser



Si3N4 double-layer achromatic metalens



InGaAsP suspended photonic crystal



Acknowledgements





